



IIU-IDB ADVANCED ELECTRONICS LABORATORIES PROJECT

Process Characterization Auxiliary Facilities-01

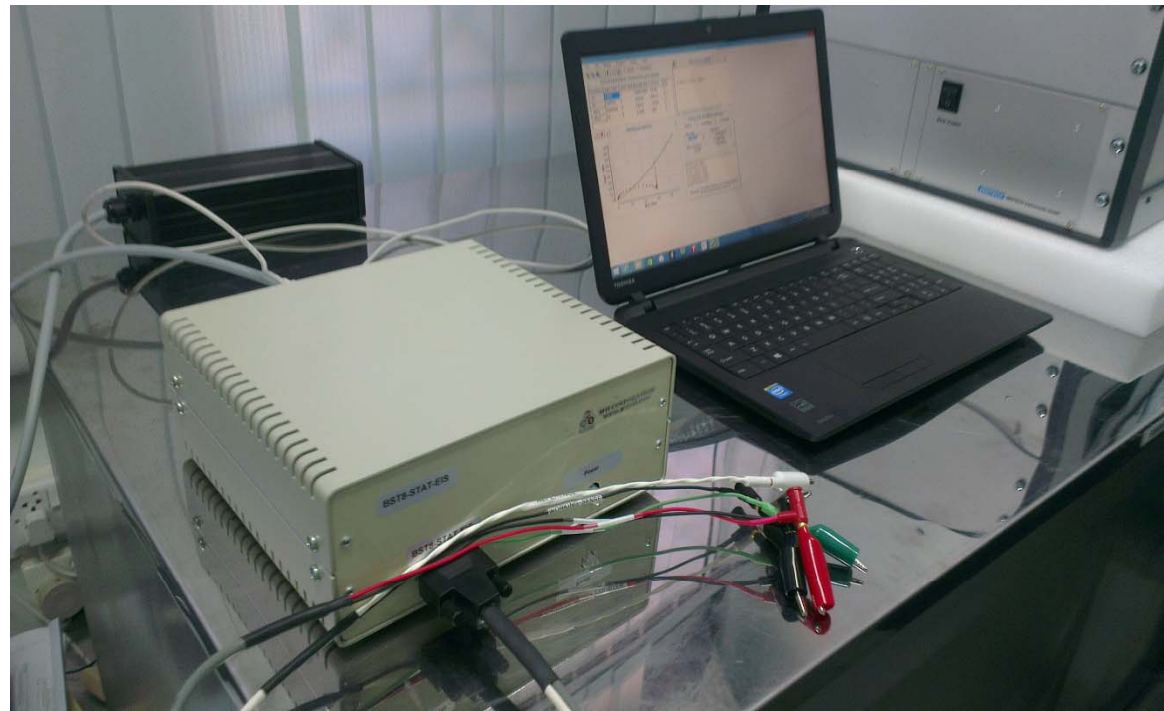
Optical Microscopy & Profilometry

Optical profilometry is a rapid, nondestructive, and noncontact surface metrology technique with options such as Reflected bright field/dark field illumination, Polarized light, DIC, etc.



Electro-Chemical Impedance Spectroscopy

This device is used for many types of electrochemical impedance specific analysis including cyclic voltammetry, corrosion studies, coating, plating, polarography, pulse voltammetry, potential sweep, controlled current, battery cycling and numerous other experiments.



Principal Investigator: Prof. Dr. Ahmed Shuja Syed